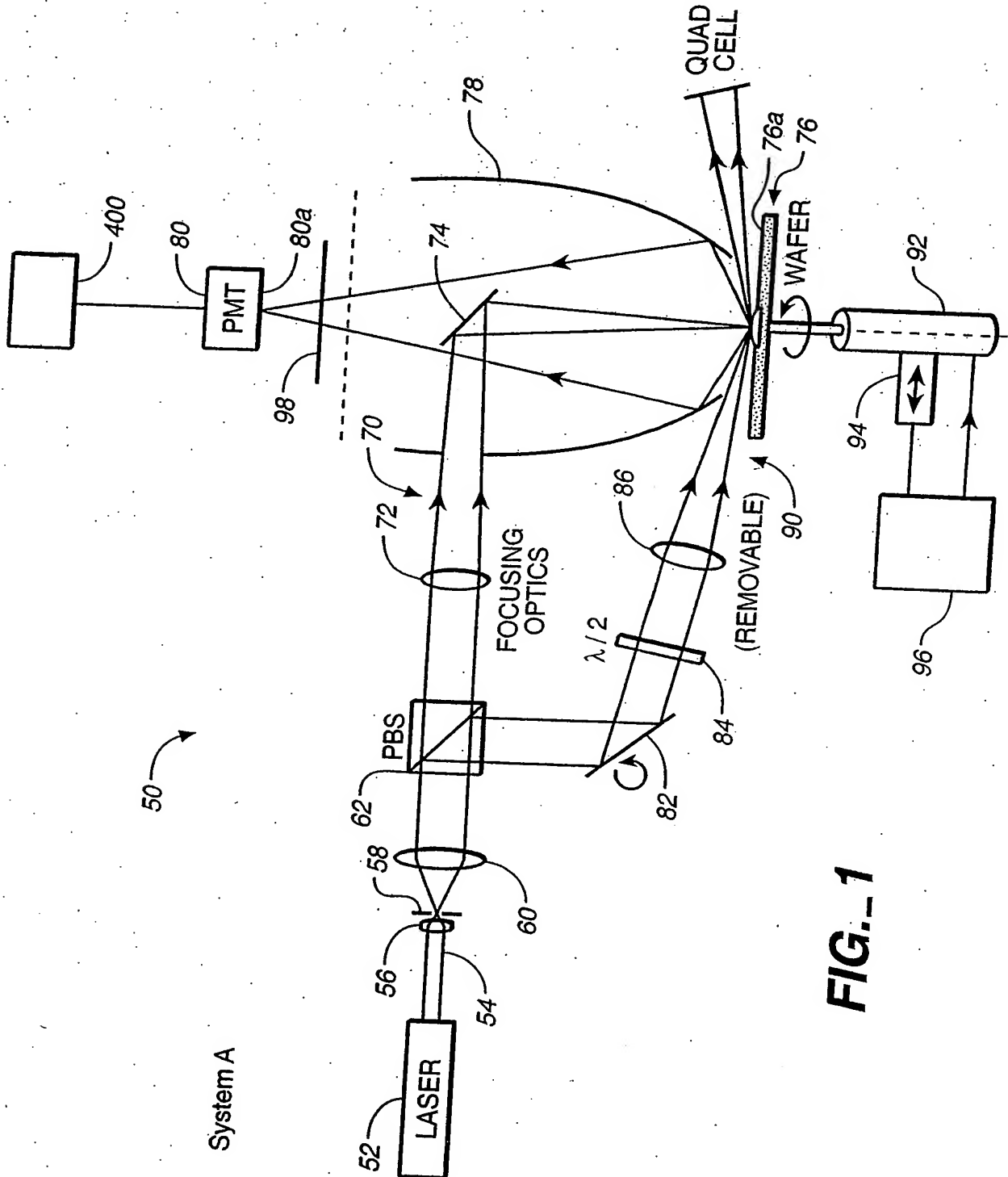
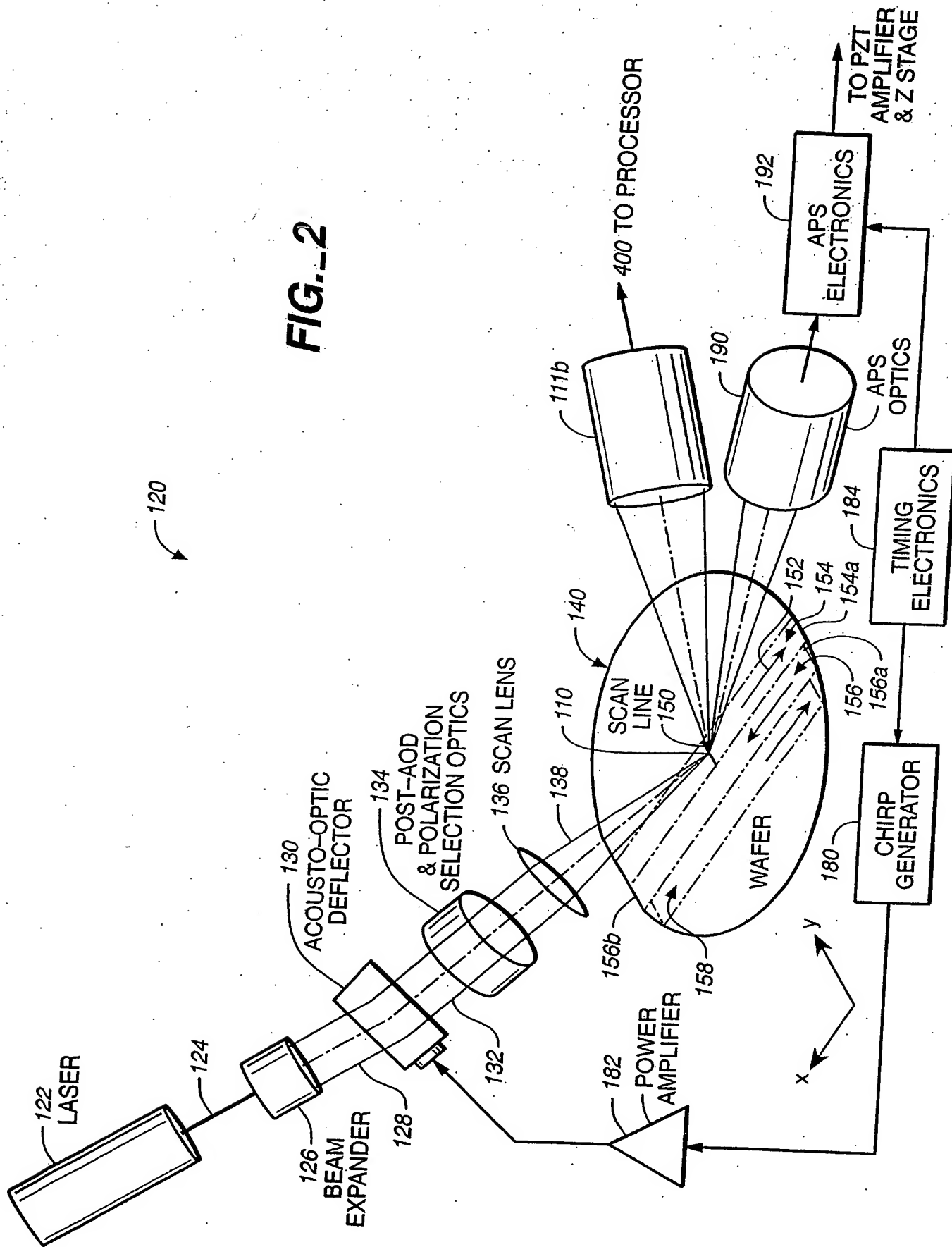


1/8

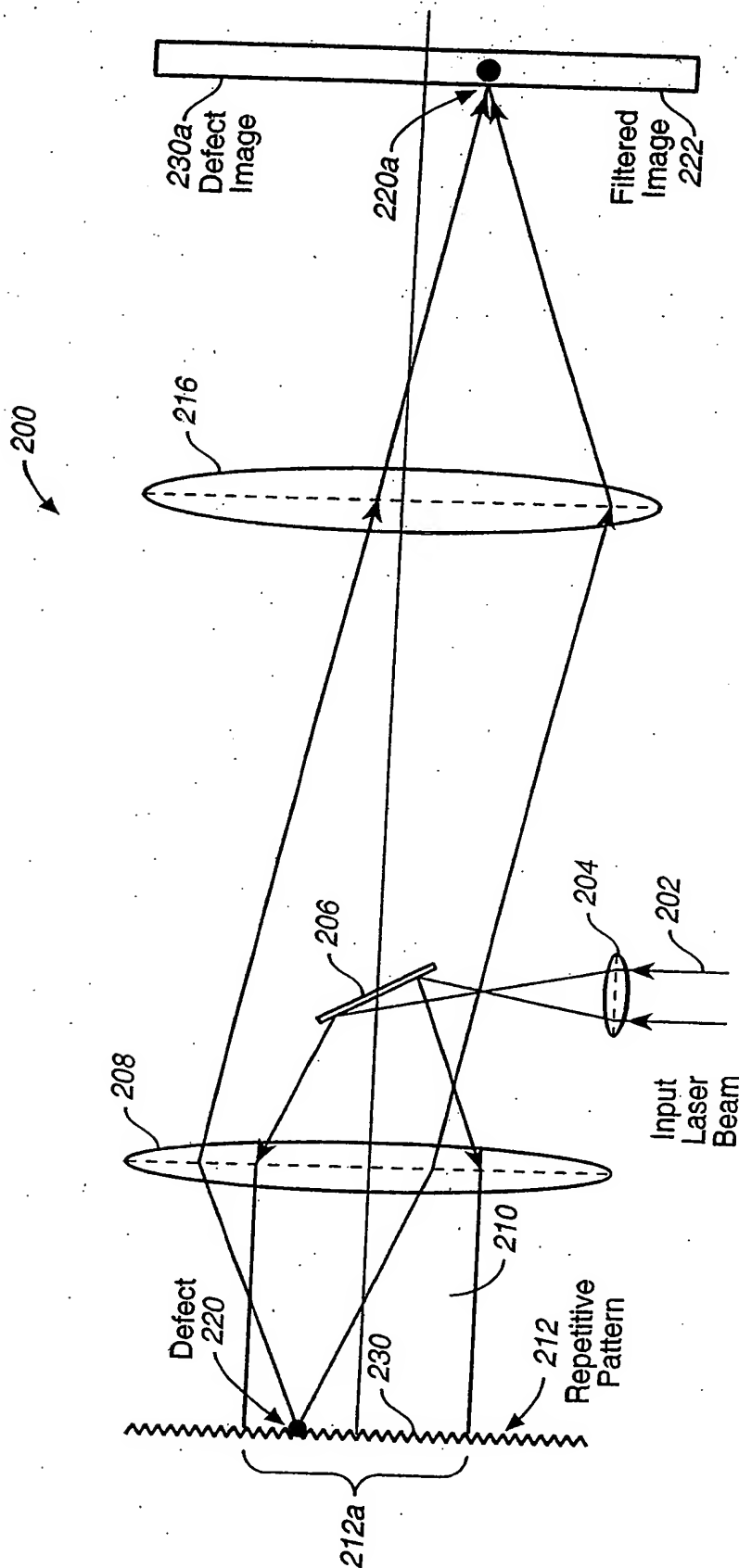


2/8

FIG. 2



3/8



Optical Pattern Filtering Defect Detection

FIG. 3

4/8

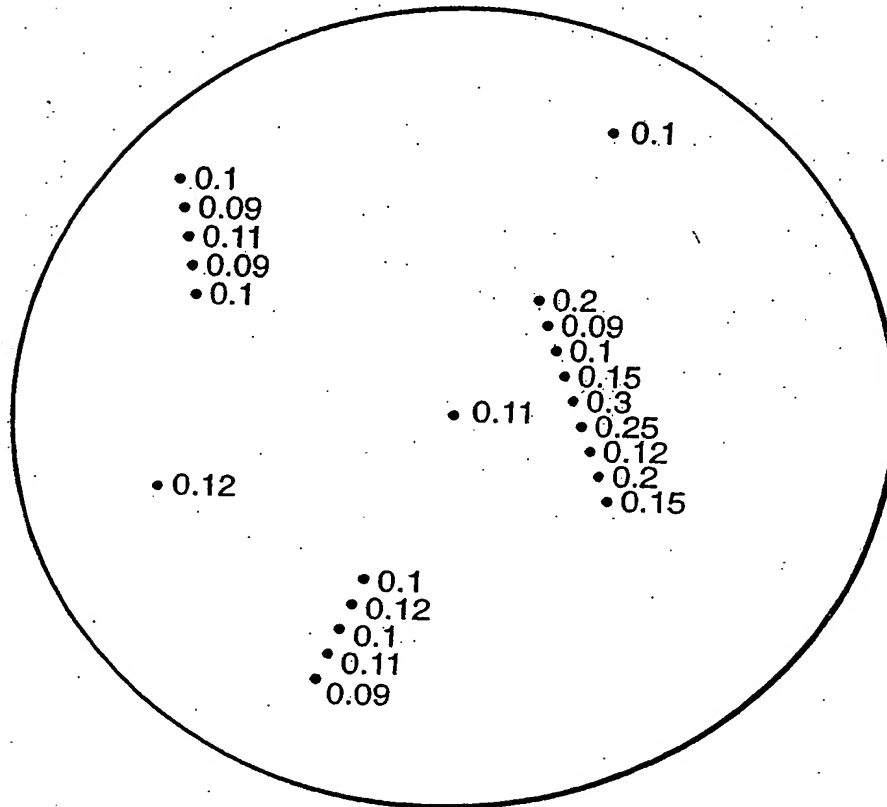


FIG. 4 Simulated Distribution of Defects After a Scan. Size Indicated in Microns

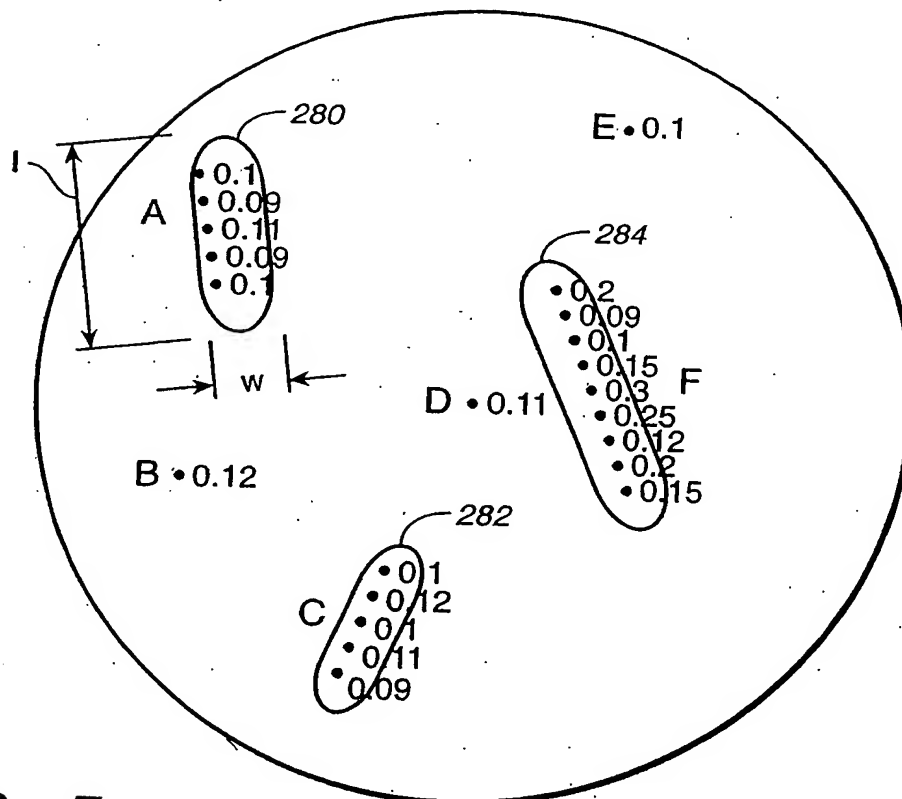
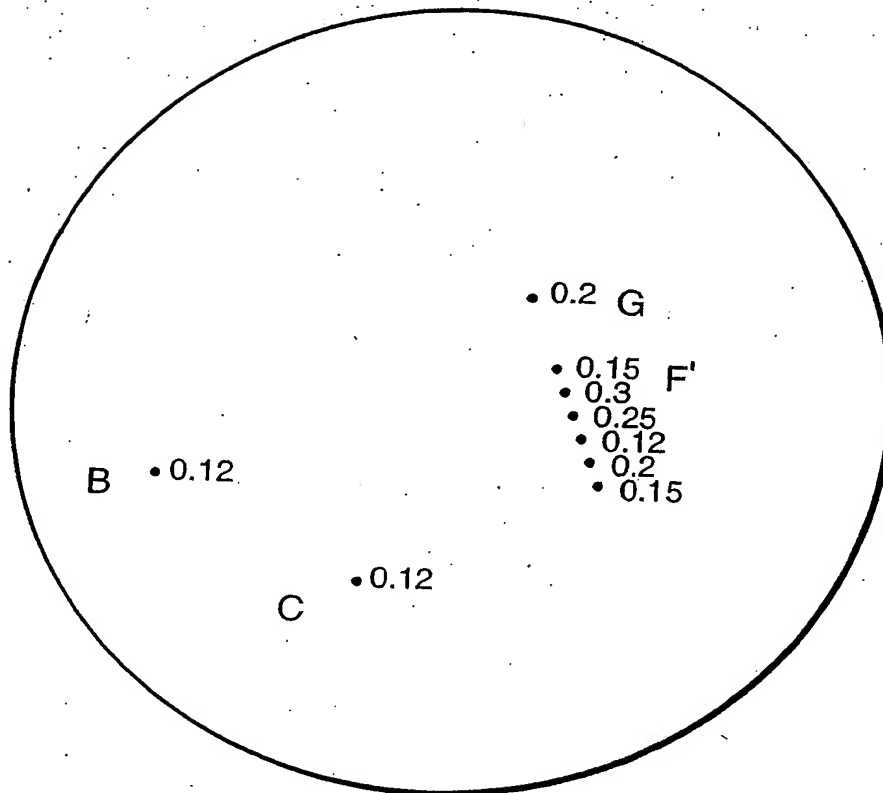


FIG. 5 Initial Clustering in Microscratch Algorithm

5/8



Final Output of the Microscratch Algorithm

FIG._6

6/8

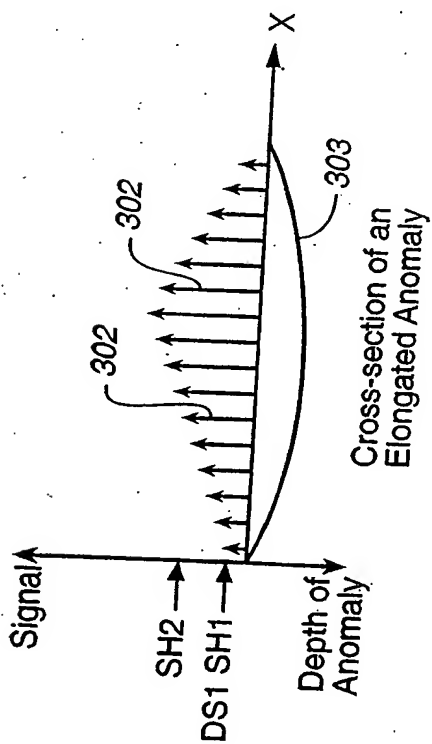


FIG. 7A

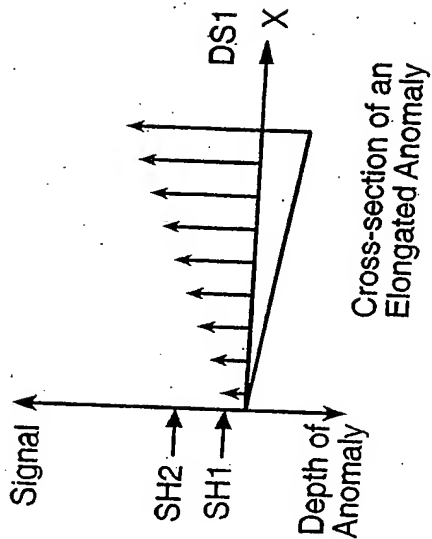


FIG. 7B

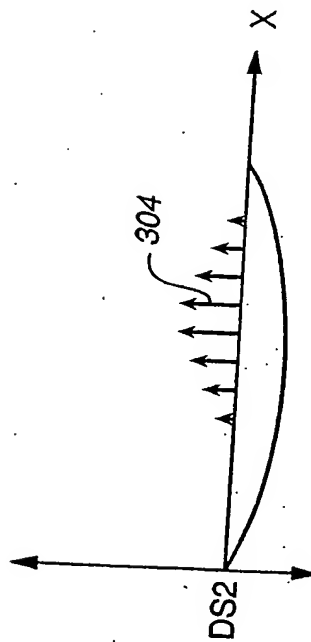


FIG. 8A

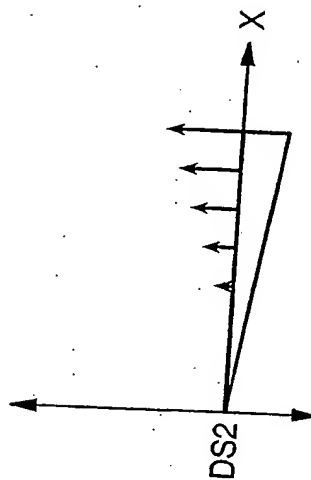


FIG. 8B

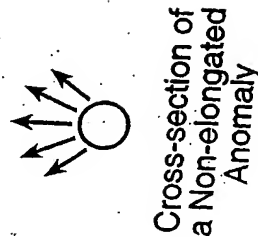


FIG. 9

7/8

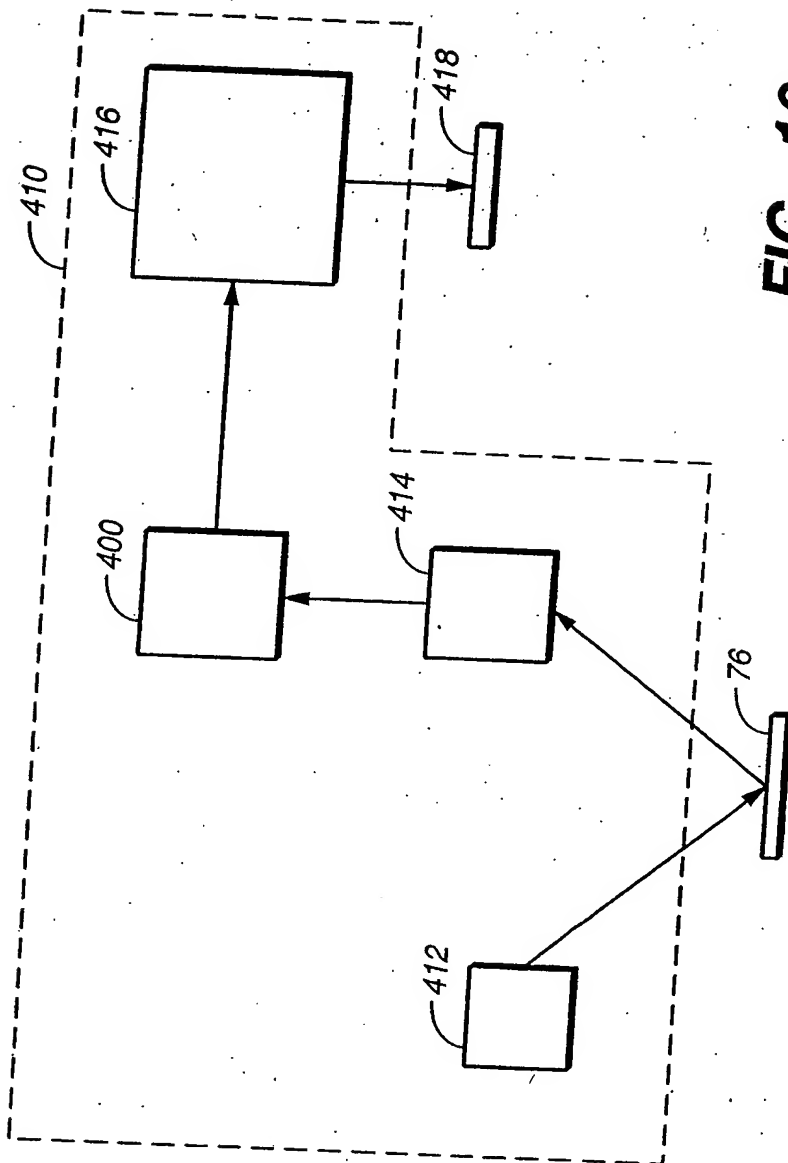


FIG. 10

8/8

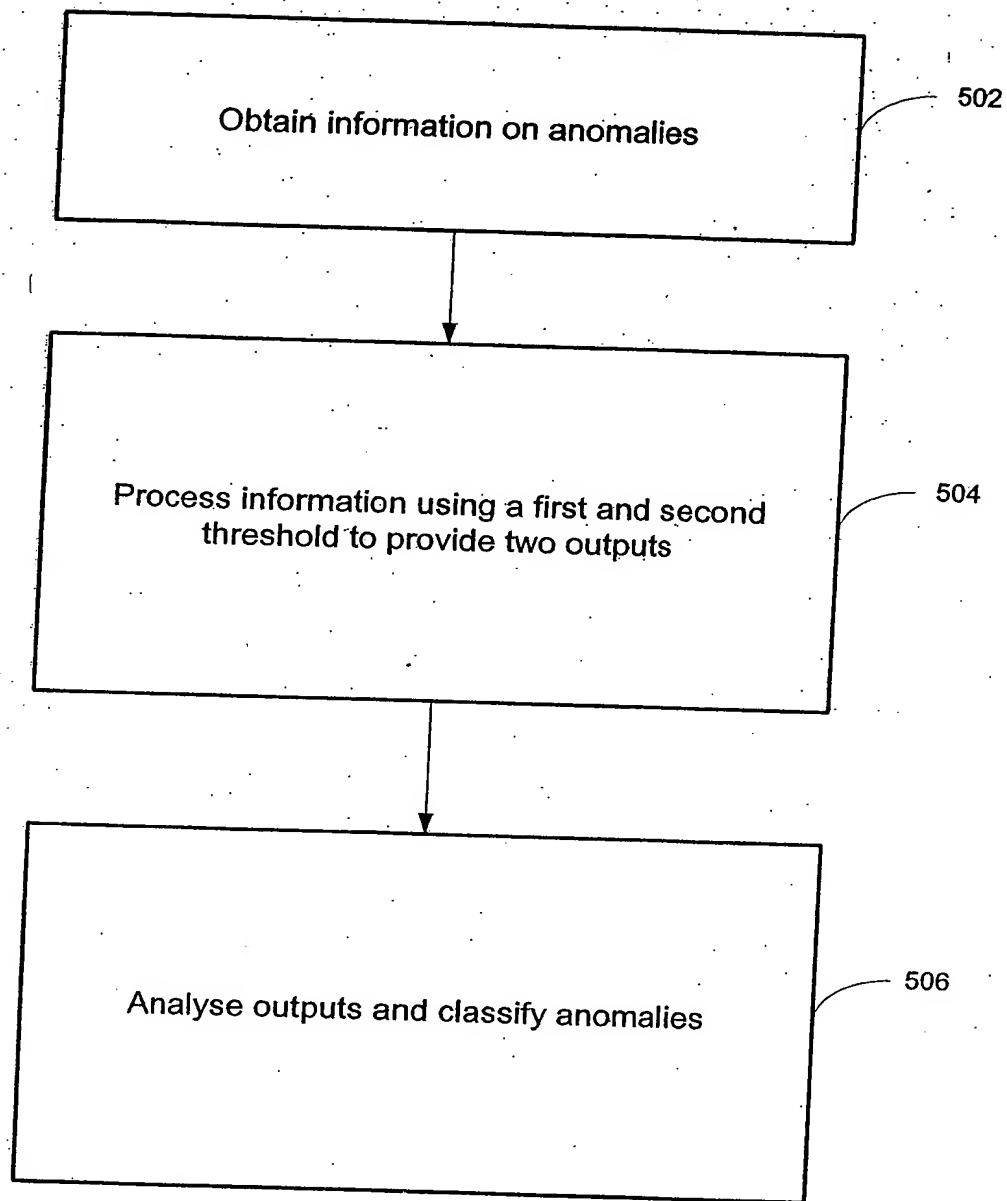


FIG. 11